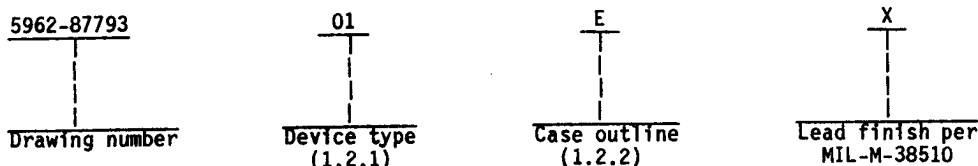


1. SCOPE

1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:



1.2.1 Device type. The device type shall identify the circuit function as follows:

Device type	Generic number	Circuit function
01	10586	Hex D-type flip-flop with common reset

1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter	Case outline
E	D-2 (16-lead, .840" x .310" x .200"), dual-in-line package
F	F-5 (16-lead, .440" x .285" x .085"), flat package
2	C-2 (20-terminal, .358" x .358" x .100"), square chip carrier package

1.3 Absolute maximum ratings.

Supply voltage range ($V_{CC} = 0.0$ V) - - - - -	-8.0 V dc to 0.0 V dc
Input voltage range ($V_{CC} = 0.0$ V) - - - - -	0.0 V dc to -5.2 V dc
Storage temperature range - - - - -	-65°C to +150°C
Lead temperature (soldering, 10 seconds) - - - - -	+300°C
Junction temperature (T_J) - - - - -	+165°C
Maximum power dissipation (P_D) - - - - -	698 mW
Thermal resistance, junction-to-case (θ_{JC}) - - - - -	See MIL-M-38510, appendix C

1.4 Recommended operating conditions.

Supply voltage range (V_{EE}) - - - - -	-5.46 V dc minimum to -4.94 V dc maximum
Ambient operating temperature range (T_A) - - - - -	-55°C to +125°C
Minimum high level input voltage (V_{IH}):	
$T_A = +25^\circ\text{C}$ - - - - -	-0.780 V dc
$T_A = +125^\circ\text{C}$ - - - - -	-0.630 V dc
$T_A = -55^\circ\text{C}$ - - - - -	-0.880 V dc
Maximum low level input voltage (V_{IL}):	
$T_A = +25^\circ\text{C}$ - - - - -	-1.850 V dc
$T_A = +125^\circ\text{C}$ - - - - -	-1.820 V dc
$T_A = -55^\circ\text{C}$ - - - - -	-1.920 V dc
Minimum setup time (t_s) - - - - -	2.5 ns
Minimum hold time (t_h) - - - - -	1.5 ns

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2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.2 Truth table. The truth table shall be as specified on figure 2.

3.2.3 Test circuit and switching waveforms. The test circuit and switching waveforms shall be as specified on figure 3.

3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full ambient operating temperature range.

3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C < T _A < +125°C Unless otherwise specified	Group A subgroups	Limits		Unit		
				Min	Max			
Cases E, F, and 2		Quiescent tests 1/ 2/						
High level output voltage	V _{OH}	Outputs terminated through 100n to -2 V V _{CC} = 0.0 V V _{EE} = -5.2 V	V _{IH}	V _{IL}				
			1	-0.780	-1.850	-0.930	-0.780	V
			2	-0.630	-1.820	-0.825	-0.630	
Low level output voltage	V _{OL}	3/	1	-0.780	-1.850	-1.850	-1.620	V
			2	-0.630	-1.820	-1.820	-1.545	
			3	-0.880	-1.920	-1.920	-1.655	
High level threshold output voltage	V _{OHA}		1	-1.105	-1.475	-0.950	-0.780	V
			2	-1.000	-1.400	-0.845	-0.630	
			3	-1.255	-1.510	-1.100	-0.880	
Low level threshold output voltage	V _{OLA}		1	-1.105	-1.475	-1.850	-1.600	V
			2	-1.000	-1.400	-1.820	-1.525	
			3	-1.255	-1.510	-1.920	-1.635	
Power supply drain current	I _{EE}	V _{EE} = -5.46 V V _{CC} = 0.0 V V _{IH} = -0.780 V at +25°C -0.630 V at +125°C -0.880 V at -55°C	1 2,3	-110 -121		mA		
High level input current	I _{IH1}		Data inputs	1 2,3	220 375	μA		
	I _{IH2}		Clock input	1 2,3	310 525	μA		
	I _{IH3}		Reset input	1 2,3	575 975	μA		
Low level input current	I _{IL}	V _{EE} = -4.94 V V _{CC} = 0.0 V V _{IL} = -1.850 V at +25°C -1.820 V at +125°C -1.920 V at -55°C	1,3 2	0.5 0.3		μA		

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C < T _A < +125°C Unless otherwise specified	Group A subgroups	Limits		Unit
				Min	Max	
Cases E, F, and 2		AC tests				
Transition time	t _{TLH} , t _{THL}	V _{EE} = -3.2 V V _{CC} = +2.0 V C _L ≤ 5 pF R _L = 100Ω See figure 3	9	1.1	4.0	ns
			10	1.0	4.7	
			11	1.0	4.3	
Propagation delay time, clock to output	t _{PHH} , t _{PHL1}		9	1.6	4.5	ns
			10	1.6	5.3	
			11	1.6	4.9	
Propagation delay time, reset to output	t _{PHL2}		9	1.6	4.5	ns
			10	1.6	5.3	
			11	1.6	4.9	
Maximum clock frequency	f _{MAX}		9	125		MHz
			10	125		
			11	125		

1/ The quiescent limits are determined after a device has reached thermal equilibrium. This is defined as the reading taken with the device in a socket with > 500 LFPM of +25°C, +125°C or -55°C (as applicable) air blowing on the unit in a transverse direction with power applied for at least 4 minutes before the reading is taken. This method was used for theoretical limit establishment only.

2/ The ΔT test method creates the limits and test conditions to be used after an increased ambient temperature has been stabilized by external thermal sources. This adjusted temperature simulates the quiescent method by increasing the specified case temperature (+25°C, +125°C, -55°C) with a ΔT. The ΔT is theoretically determined based on the power dissipation and thermal characteristics of the device and package used.

3/ The high and low level output current varies with temperature, and can be calculated using the following formula: I_{OH} = (V_{OH} - 2 V)/100Ω and I_{OL} = (V_{OL} - 2 V)/100Ω.

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Cases outlines	E	F	2
Terminal number	Terminal symbol		
1	RESET	Q3	NC
2	Q0	Q4	RESET
3	Q1	Q5	Q0
4	Q2	V _{CC}	Q1
5	D0	RESET	Q2
6	D1	Q0	NC
7	D2	Q1	D0
8	V _{EE}	Q2	D1
9	CLOCK	D0	D2
10	D3	D1	V _{EE}
11	D4	D2	NC
12	D5	V _{EE}	CLOCK
13	Q3	CLOCK	D3
14	Q4	D3	D4
15	Q5	D4	D5
16	V _{CC}	D5	NC
17	---	---	Q3
18	---	---	Q4
19	---	---	Q5
20	---	---	V _{CC}

NC = No connection

FIGURE 1. Terminal connections.

Reset	Clock*	Q _n	Q _{n+1}
L	L	X	Q _n
L	H	L	L
L	H	H	H
H	L	X	L

L = Low level
H = High level
X = Irrelevant

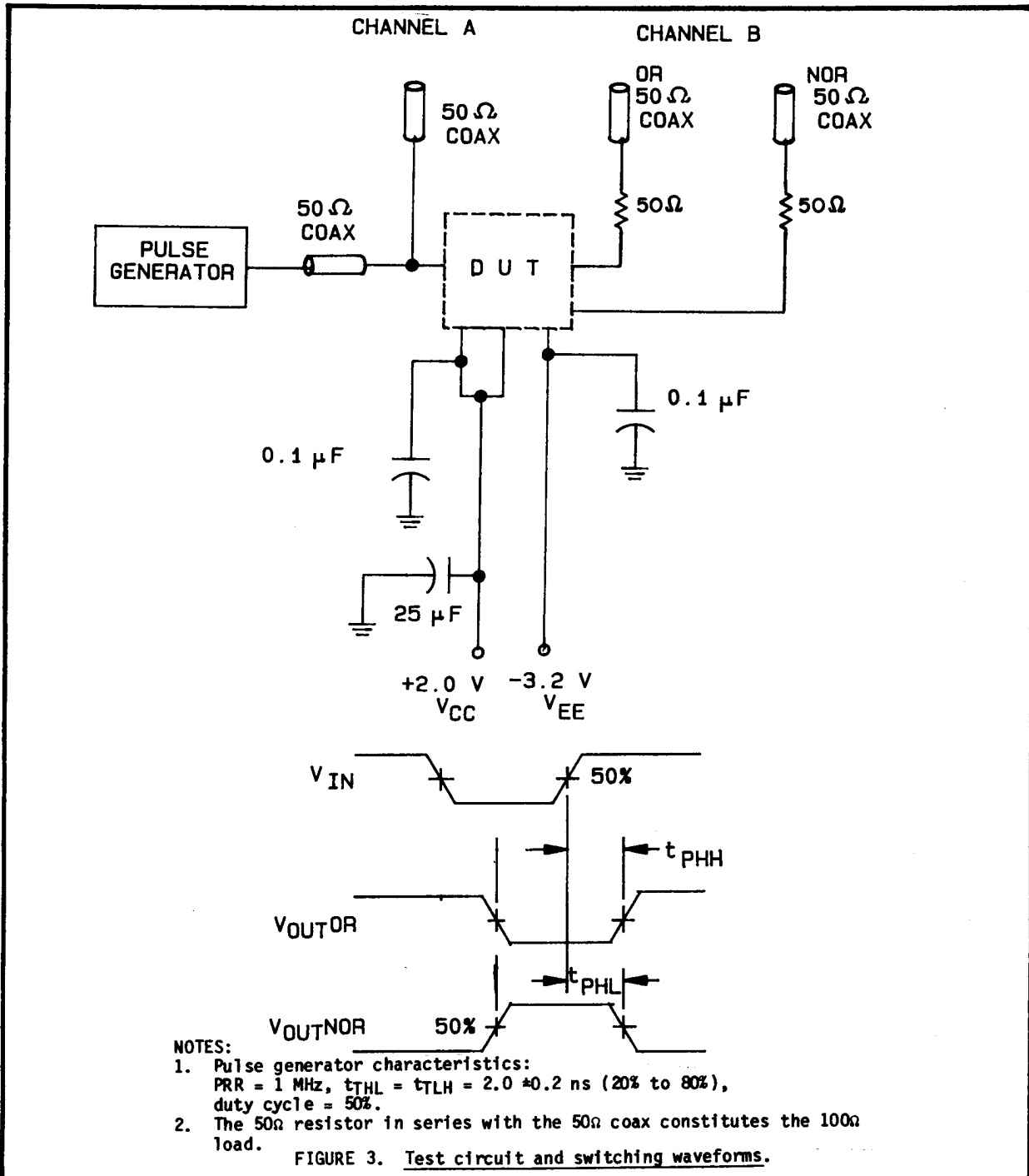
*A clock high is a clock transition from low to high

FIGURE 2. Truth table.

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3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

4. **QUALITY ASSURANCE PROVISIONS**

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

- a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition D, or E using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}\text{C}$, minimum.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 4, 5, and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
- c. Subgroups 7 and 8 tests shall verify the truth table as specified on figure 2 herein.

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - (1) Test condition D, or E using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}\text{C}$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	1
Final electrical test parameters (method 5004)	1*, 2, 3, 7*, 8, 9
Group A test requirements (method 5005)	1, 2, 3, 7, 8, 9, 10, 11
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

* PDA applies to subgroups 1 and 7.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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6.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	Vendor similar part number <u>1/</u>
5962-8779301EX	04713	10586/BEAJC
5962-8779301FX	04713	10586/BFAJC
5962-87793012X	04713	10586M/B2AJC

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

04713

Vendor name and address

Motorola, Incorporated
7402 South Price Road
Tempe, AZ 85283

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